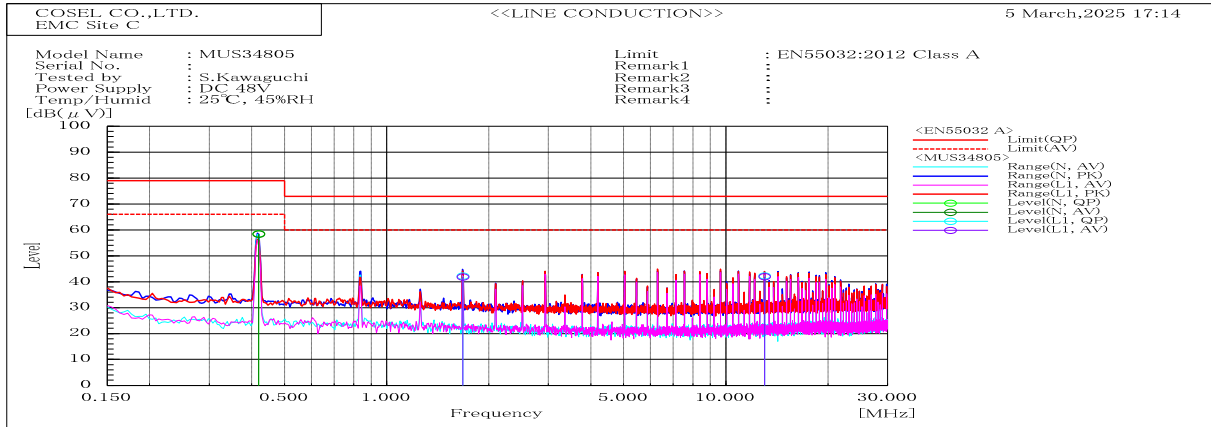
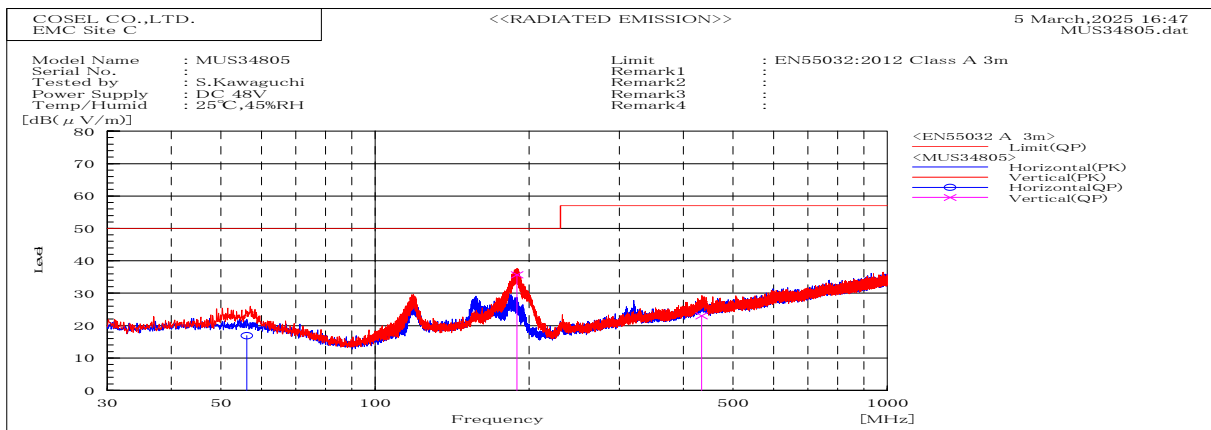


DATA SHEET		Date	05-Mar-25
Model	MUS34805	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	45 %RH
		Tested by	S.Kawaguchi



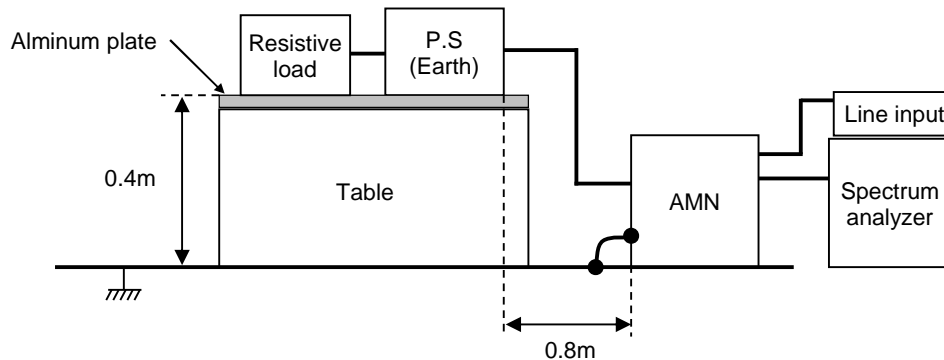
Frequency MHz	Line	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
1.679	L1	42.2	41.8	73	60	30.8	18.2	Pass	
13.012	L1	42.3	41.9	73	60	30.7	18.1	Pass	
0.42	N	58.5	58.4	79	66	20.5	7.6	Pass	



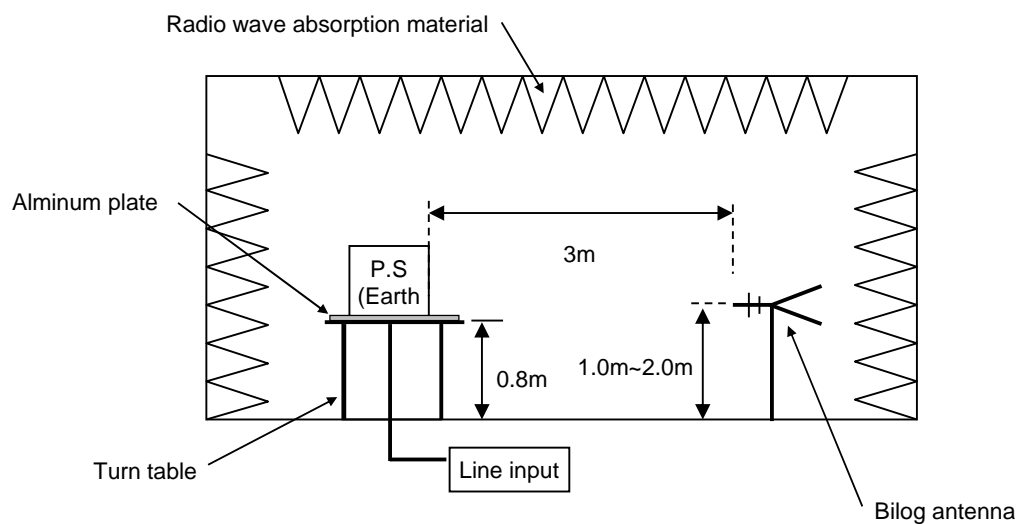
Frequency MHz	Polarization	Stability	Level dB(μV/m)		Limit dB(μV/m)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV						
189.327	V	Stable	35.7	35.7	50	14.3	Pass	100	51.5	
56.234	H	Stable	16.9	16.9	50	33.1	Pass	109.4	349.7	
433.768	V	Stable	23	23	57	34	Pass	138.8	210.4	

DATA SHEET		Date	05-Mar-25
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	45 %RH
		Tested by	S.Kawaguchi

1. Line conduction



2. Radiated emission



Conditions

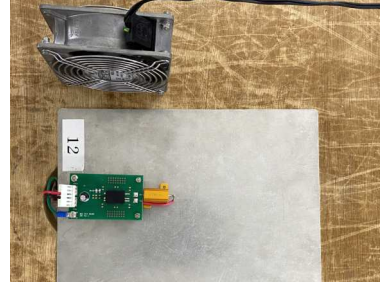
Test : EMI
Model Name: MUS3□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

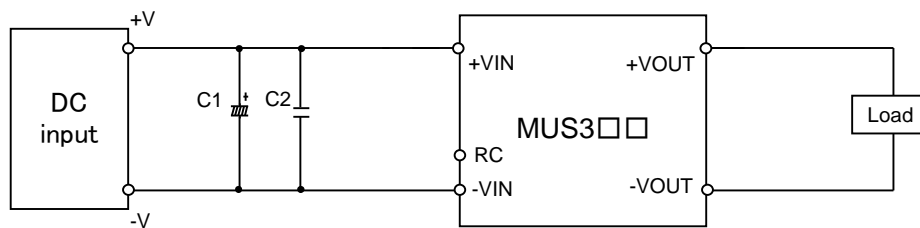


Fig.1 MUS305□, MUS312□, MUS324□ Testing circuitry

C1 :	MUS305□	16V 220 μ F	Electric capacitor (UPWseries NICHICON)
	MUS312□	50V 100 μ F	Electric capacitor (UPWseries NICHICON)
	MUS324□	-	
C2 :	MUS305□	16V 22 μ F	Ceramic capacitor (GRM31CC71C226M MURATA MANUFACTURING)
	MUS312□	25V 22 μ F	Ceramic capacitor (C3216JB1E226MT TDK)
	MUS324□	50V 10 μ F	Ceramic capacitor (C3216X7R1H106KT TDK)

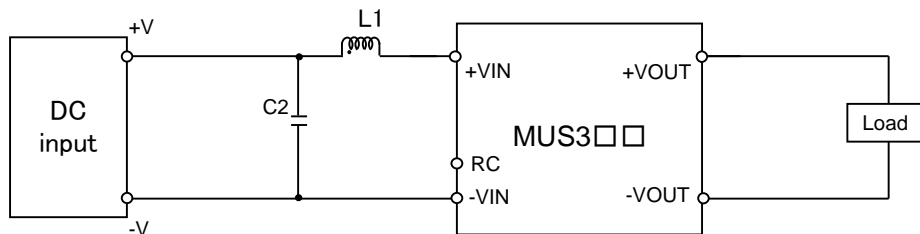


Fig.2 MUS348□ Testing circuitry

C2 :	MUS348□	100V 2.2 μ F	Ceramic capacitor (C3216X7S2A225KT TDK)
L1 :	MUS348□	520mA 15 μ H	Inductor(LQH32PN150MN0L MURATA MANUFACTURING)